

## 簡 歷

### 基本資料：

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### 主要學經歷：

畢業學校	主修學系	學位	起迄年月
交通大學	光電工程研究所	博士	90/9-93/6
交通大學	光電工程研究所	碩士	89/9-90/6
中原大學	物理學系	學士	86/9-89/6

## 著作 (Publication List)

### (A) 期刊論文：

1. **Kun-Huang Chen**, Cheng-Chih Hsu, and Der-Chin Su, "Measurement of wavelength shift by using surface plasmon resonance heterodyne interferometry," *Opt. Commun.* **209**, 167-172 (2002).
2. Cheng-Chih Hsu, **Kun-Huang Chen**, and Der-Chin Su, "Normal incidence refractometer," *Opt. Commun.* **218**, 205-211 (2003).
3. **Kun-Huang Chen**, Cheng-Chih Hsu, and Der-Chin Su, "Measurement of the concentration of a solution with the surface plasmon resonance heterodyne interferometry," *Opt. Eng.* **42**, 1884-1887 (2003).
4. **Kun-Huang Chen**, Cheng-Chih Hsu, and Der-Chin Su, "Interferometric optical sensor for measuring glucose concentration," *Appl. Opt.* **42**, 5774-5776 (2003).
5. **Kun-Huang Chen**, Cheng-Chih Hsu, and Der-Chin Su, "A method for measuring the complex refractive index and thickness of a thin metal film," *Appl. Phys. B.* **77**, 839-842 (2003).
6. Jiun-You Lin, **Kun-Huang Chen**, and Der-Chin Su, "Improved method for measuring small optical rotation angle of chiral liquid," *Opt. Commun.* was accepted and will be published (2004).
7. Cheng-Chih Hsu, **Kun-Huang Chen**, Jiun-You Lin, and Der-Chin Su, "Simultaneous determination of the refractive index and thickness of thick weakly absorbing film and non-absorbing substrate," submitted manuscript to *Opt. Eng.* (2004).
8. **Kun-Huang Chen**, Jiun-You Lin, and Der-Chin Su, "Comparison of Kretschmann-Raether angular and thickness regimes with phase-difference shift for measuring changes in refractive index," paper in preparing.

(B) 研討會論文：

1. 陳坤煌、許正治、蘇德欽，〈利用表面電漿波及外差干涉術測量液體濃度〉 2001 台灣光電科技研討會，高雄，2001 年 12 月，論文集 849-852.
2. Cheng-Chih Hsu, Kun-Huang Chen, and Der-Chin Su, "An optical configuration for measuring complex refractive index and thickness of thin film," 2002 International Topical Meeting on Optics in Computing, Taipei, Taiwan, Apr. 2002, Proceedings, 401-403.
3. Cheng-Chih Hsu, Kun-Huang Chen, and Der-Chin Su, "Identification of thin metal film on surface plasma probe by using heterodyne interferometry," 5th International Conference on Application of Photonic Technology, Quebec, Canada, May. 2002, SPIE 4833, 255-262.
4. Der-Chin Su, Kun-Huang Chen, and Cheng-Chih Hsu, "A method for measuring the concentration of a solution," 19th Congress of the International Commission for Optics, Firenze, Italy, Aug. 2002, SPIE 4829, 843-844.
5. 許正治、陳坤煌、蘇德欽，〈以垂直入射旋光外差干涉術測量介質之折射率〉 2002 台灣光電科技研討會，台北市，2002 年 12 月，論文集 28-30.
6. 陳坤煌、許正治、蘇德欽，〈新型低葡萄糖溶液濃度計〉 2002 台灣光電科技研討會，台北市，2002 年 12 月，論文集 450-452.
7. Jiun-You Lin, Kun-Huang Chen, and Der-Chin Su, "An alternative method for measuring the chiral parameter and the average refractive index of a chiral liquid," 2003 International Conference on Laser Applications and Optical Metrology, New Delhi, India, Dec. 2003, Proceedings, 326-330.
8. Kun-Huang Chen, Jiun-You Lin, and Der-Chin Su, "A new type of sensor for measuring the small refractive index difference of solutions," 2003 International Conference on Laser Applications and Optical Metrology, New Delhi, India, Dec. 2003, Proceedings, 527-531.
9. 陳坤煌、林俊佑、蘇德欽，〈使用測量表面電漿共振相位差應用的最佳條件探討〉 2003 台灣光電科技研討會，台北市，2003 年 12 月，論文集 565-567.

10. Der-Chin Su, Jing-Heng Chen, **Kun-Huang Chen**, and Jiun-You Lin ” Surface plasmon resonance heterodyne interferometry for measuring physical parameters,” Photonics Europe 2004, France, Strasbourg, Apr. 2004, SPIE.

### (C) 專書、技術報告等

1. 蘇德欽、許正治、**陳坤煌**， <垂直入射型折射率計>， <<光訊(OPTO NEWS & LETTERS)>>， **103期**， 22-25 (2003).

### (D) 專利

發明專利(中國)：「垂直入射型折射率測量裝置」，審查中，2003。

